

STG3P3M25N60

3 phase inverter IGBT - SEMITOP®3 module

Features

- Low on-voltage drop (V_{CE(sat)})
- Low C_{RES} / C_{IES} ratio (no cross-conduction susceptibility)
- Very soft ultra fast recovery antiparallel diode
- High frequency operation up to 70 kHz
- One screw mounting
- Compact design
- Semitop[®]3 is a trademark of Semikron

Applications

- High frequency inverters
- Motor drivers

Description

Using the latest high voltage technology based on a patented strip layout, STMicroenctionics has designed an advanced family of IGBTs, the PowerMESHTM IGBT is it in outstanding performances.

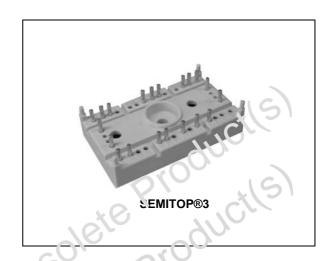


Figure 1. Internal schematic diagram

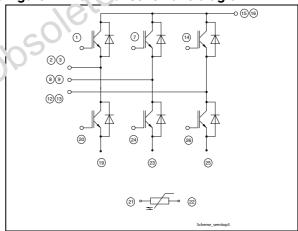


Table 1. Device summary

Order code	Marking	Package	Packaging
STG3P3M25N60	G3P3M25N60	SEMITOP®3	Semibox

Contents STG3P3M25N60

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STG3P3M25N60 **Electrical ratings**

Electrical ratings 1

Table 2. **Absolute maximum ratings**

Symbol	Parameter	Value	Unit
V _{CES}	Collector-emitter voltage (V _{GE} = 0)	600	V
I _C ⁽¹⁾	Collector current (continuous) at T _s = 25 °C	50	Α
I _C ⁽¹⁾	Collector current (continuous) at T _s = 80 °C	25	Α
V _{GE}	Gate-emitter voltage	±20	٧
I _{CM} ⁽²⁾	Collector current (pulsed, tp < 1 ms) Ts=25 °C	100	A
I _{CM} ⁽²⁾	Collector current (pulsed, tp < 1 ms) Ts=80 °C	50	Α
I _F	Diode RMS forward current at T _s = 25 °C	13	Α
P _{TOT}	Total dissipation at T _s = 25 °C	96	W
V _{ISO}	Insulation withstand voltage A.C. (t=1 min/sec; T _s = 25 °C)	2500/3000	V
T _{stg}	Storage temperature	- 40 to 125	°C
T _j	Operating junction temperat re	- 40 to 150	°C

^{1.} Calculated value

Parameter	Value
ce junction-sink ⁽¹⁾ max.	1.3
	nce junction-sink ⁽¹⁾ max. ve grease applied and maximum mounting

STG3P3M25N60 **Electrical characteristics**

2 **Electrical characteristics**

(T_s= 25 °C unless otherwise specified)

Table 4. **IGBT-Inverter parameters**

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)CES}	Collector-emitter breakdown voltage (V _{GE} = 0)	I _C = 1 mA	600			V
I _{CES}	Collector cut-off current (V _{GE} = 0)	V _{CE} = 600 V V _{CE} = 600 V, T _s = 125 °C			10	μA nA
I _{GES}	Gate-emitter leakage current (V _{CE} = 0)	V _{GE} = ±20 V	5-	UC	±100	nA
$V_{\text{GE(th)}}$	Gate threshold voltage	$V_{CE} = V_{GE}, I_{C} = 250 \mu A$	3.75	ĺ	5.75	V
V _{CE(sat)}	Collector-emitter saturation voltage	V _{GE} = 15 V, I _C = 20 A V _{GE} =15 V, I _C = 20 A, Γ _S =125°C		1.85 1.7	2.5	V V
Table 5.	Dynamic	3/5010 PY	0	<i>)</i>		
	_		.	_		

Table 5. **Dynamic**

	Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
	g _{fs} ⁽¹⁾	Forward transconductance	V _{CE} = 15 V _, I _C = 20 A		15		S
	C _{ies} C _{oes} C _{res}	Input capacitatine Output capacitatine Reve se transfer or pacitance	$V_{CE} = 25 \text{ V, f} = 1 \text{ MHz,}$ $V_{GE} = 0$		2200 225 50		pF pF pF
76	Q _g Q _{gc}	Total gate charge Gate-emitter charge Gate-collector charge	$V_{CE} = 390 \text{ V, } I_{C} = 20 \text{ A,}$ $V_{GE} = 15 \text{ V,}$ (see Figure 9)		100 16 45	140	nC nC nC
Obsole		pulse duration=300μs, duty cycle	1.5%				

Table 6. Switching on/off

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)} t _r (di/dt) _{on}	Turn-on delay time Current rise time Turn-on current slope	V_{CC} = 300 V, I_{C} = 20 A R_{G} = 3.3 Ω , V_{GE} = ±15 V, (see Figure 10)		31 11 1600		ns ns A/µs
t _{d(on)} t _r (di/dt) _{on}	Turn-on delay time Current rise time Turn-on current slope	$V_{CC} = 300 \text{ V, } I_{C} = 20 \text{ A}$ $R_{G} = 3.3 \Omega \text{ , } V_{GE} = \pm 15 \text{ V,}$ $T_{S} = 125 ^{\circ}\text{C}$ (see Figure 10)		31 11.5 1500		ns ns A/µs
t _r (V _{off}) t _d (_{off}) t _f	Off voltage rise time Turn-off delay time Current fall time	V_{CC} = 300 V, I_{C} = 20 A R_{G} = 3.3 Ω , V_{GE} = ±15 V, (see Figure 10)		28 100 75	ile	ns ns ns
t _r (V _{off}) t _d (_{off}) t _f	Off voltage rise time Turn-off delay time Current fall time	$V_{CC} = 300 \text{ V}, I_{C} = 20 \text{ A}$ $R_{G} = 3.3 \Omega, V_{GE} = \pm 15 \text{ V},$ $T_{S} = 125 ^{\circ}\text{C}$ (see Figure 10)	10	66 150 130	ile	ns ns ns

Table 7. Switching energy (inductive load)

	Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
	$E_{on}^{(1)}$ $E_{off}^{(2)}$ E_{ts}	Turn-on switching losses Turn-off switch ing losses Total switch ng losses	V_{CC} = 300 V, I_{C} = 20 A R_{G} = 3.3 Ω , V_{GE} = ±15 V, (see Figure 10)		220 330 550		μJ μJ μJ
	E _{on} (1) E _{off} (.?)	Turn on switching losses hurn-off switching losses Total switching losses	$V_{CC} = 300 \text{ V}, I_{C} = 20 \text{ A}$ $R_{G} = 3.3 \Omega, V_{GE} = \pm 15 \text{ V},$ $T_{s} = 125 ^{\circ}\text{C}$ (see Figure 10)		450 770 1220		μJ μJ μJ
Solle	a packag		ode is used in the test circuit in figuck diode is used as external diode.				l in
On	2. Turn-off	losses include also the tail of the	collector current				
Open							

Eon is the tun-on losses when a typical diode is used in the test circuit in figure 2. If the IGBT is offered in a package with a co-pak diode, the co-pack diode is used as external diode. IGBTs & Diode are at the same temperature (25°C and 125°C)

Electrical characteristics STG3P3M25N60

Table 8. Collector-emitter diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _F	Forward on-voltage	I _F = 10 A I _F = 10 A, T _s = 125 °C		1.3 1.0	2.0	V V
t _{rr}	Reverse recovery time			44		ns
t _a		00 4 1/ 40 1/		32		ns
Q _{rr}	Reverse recovery charge	I _F = 20 A ,V _R = 40 V, di/dt = 100 A/μs		66		nC
I _{rrm}	Reverse recovery current			3		Α
S	Softness factor of the diode			0.375	LC	
t _{rr}	Reverse recovery time			88		ns
t _a		I _F = 20 A ,V _R = 40 V,	2	5()		ns
Q _{rr}	Reverse recovery charge	$di/dt = 100 \text{ A/}\mu\text{s},$	(O)	237) ,	nC
I _{rrm}	Reverse recovery current	T _s = 125 °C		5.4		Α
S	Softness factor of the diode	1016		0.57		

Table 9. **Temperature sensor**

Ta	able 9.	Temperature sensor	-105° D	10			
	Symbol	Parameter	conditions	Min.	Тур.	Max.	Unit
	R _{ts}	Equivalent resistance	5%, T _r = 25 (100) °C		5000 (493)		Ω
		AUCIL	000				
	O	100, 115)					
10	e,	AUCIL					
1050lb	0	100.0					
Ob	S						
1250/6							
Op							

2.1 Typical characteristics (curves)

lc(A)

100

80

60

40

20

Figure 2. Output characteristics at $T_s = 25$ °C

HV31880

VGE=15V

13V

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Figure 3. Output characteristics at $T_s = 125$ °C

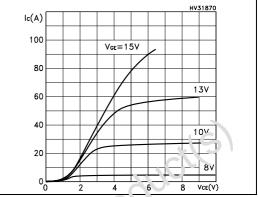
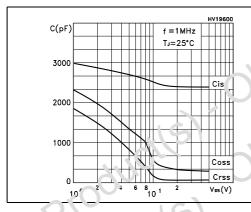


Figure 4. Capacitance variation

Figure 5. Gate charge vs gate-emitter voltage



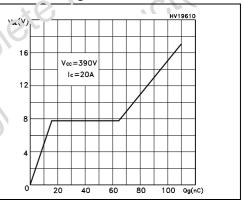
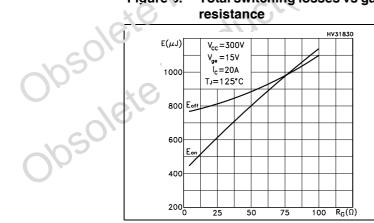
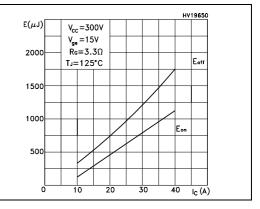


Figure 6. Total switching losses vs gate Figure 7. Total switching losses vs collector current





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Test circuits STG3P3M25N60

3 Test circuits

Figure 8. Test circuit for inductive load switching

Figure 9. Gate charge test circuit

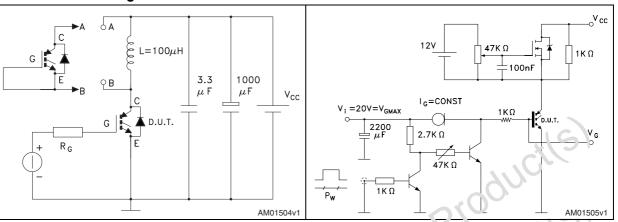
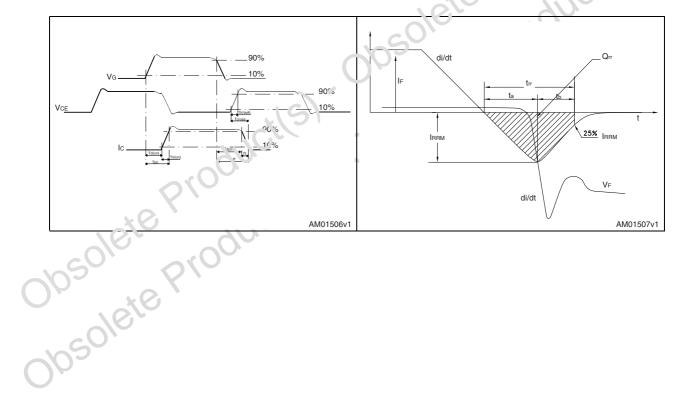


Figure 10. Switching waveform

Figure 11. Diode recovery time waveform



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4 Package mechanical data

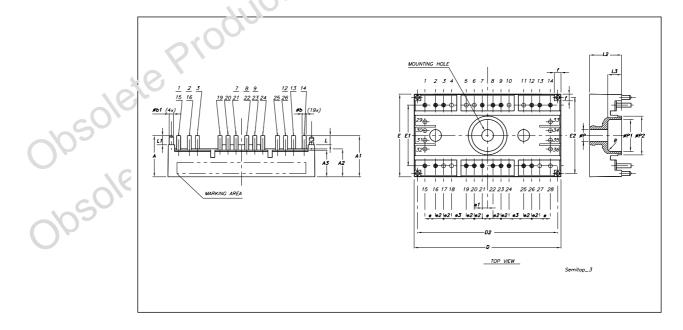
In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect . The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com

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SEMITOP®3 mechanical data

Dim	mm			
Dilli	Min	Тур	Max	
Α	15.30	15.50	15.70	
A1	15.23	15.43	15.63	
A2		10.50		
A3		10		
øb		1.50	16	
øb1		1.60	7(3)	
D	54.70	55	o <u>j.v</u>	
D2		52.50	1.10	
Е	30.70	31	31.30	
E1	22.55	22.75	23	
E2		28.50		
е	3.90	4	4.10	
e1		2		
e2	2.90		3.10	
e3	5.40	٤٠٥٥	5.60	
f		2.50		
L		3.43		
L1		3.50		
L2	11.80	12	12.20	
L3		5.20		
øΡ	4.30	4.40	4.50	
øP1		12		
øp2	1.6	14.50		
R	1151	1		
	SEMITOP®3 is a trad	emark of SEMIKRON		



STG3P3M25N60 Revision history

5 Revision history

Table 10. Revision history

Date	Revision	Changes
29-May-2006	1	Initial release
02-Oct-2008	2	 Updated Figure 6 and Figure 7 Document status promoted from preliminary data to datasheet.

Obsolete Products). Obsolete Products) Obsolete Products). Obsolete Products)

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